# EMC TEST REPORT



Report No.: 17020741-CE-E Supersede Report No.: N/A			
Applicant	SAHAB TECHNOLOGY		
Product Name	EXPANSION MODULE		
Main Model No.	XT-23EXP		
Serial Model	N/A		
Test Standard	EN 55032: 2015, EN 55024: 2010, EN 61000-3-2:2014, E	N 61000-3-3:2013	
Test Date	7th August to 8th August, 2016	7th August to 8th August, 2016	
Issue Date	29th June, 2017		
Test Result	Test Result Pass Fail		
Equipment complied with the specification			
Equipment did not comply with the specification			
Louise	Tu		
Louise T Test Engin			
This test report may be reproduced in full only Test result presented in this test report is applicable to the tested sample only			

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# Laboratories Introduction

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#### Accreditations for Conformity Assessment

Country/Region	Scope
USA	EMC, RF/Wireless, SAR, Telecom
Canada	EMC, RF/Wireless, SAR, Telecom
Taiwan	EMC, RF, Telecom, SAR, Safety
Hong Kong	RF/Wireless, SAR, Telecom
Australia	EMC, RF, Telecom, SAR, Safety
Korea	EMI, EMS, RF, SAR, Telecom, Safety
Japan	EMI, RF/Wireless, SAR, Telecom
Singapore	EMC, RF, SAR, Telecom
Europe	EMC, RF, SAR, Telecom, Safety



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# 1. <u>Report Revision History</u>

Report No.	Report Version	Description	Issue Date
16020960-CE-E	NONE	Original	9th August, 2016
17020741-CE-E	NONE	Multiple Listing	29th June, 2017

# 2. Customer information

Applicant Name	SAHAB TECHNOLOGY
Applicant Address	Ofiice 21,Qibla Tower,Fahad Al Salem St.,Qibla, State of KUWAIT
Manufacturer Name	SAHAB TECHNOLOGY
Manufacturer Address	Ofiice 21,Qibla Tower,Fahad Al Salem St.,Qibla, State of KUWAIT

# 3. <u>Test site information</u>

Lab performing tests	SIEMIC (Nanjing-China) Laboratories
	2-1 Longcang Avenue Yuhua Economic and
Lab Address	Technology Development Park, Nanjing, China
FCC Test Site No.	986914
IC Test Site No.	4842B-1
Test Software	EZ_EMC (Ver.ICP-03A1)



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# **4.** Equipment Under Test (EUT) InformationDescription of EUT:EXPANSION MODULEMain Model:XT-23EXPSerial Model:N/ADate EUT received:25th July, 2016Test Date(s):7th August to 8th August, 2016

Port:

Power:

Trade Name :

**Highest Operate Frequency** 

# KonTel

OUTPUT: DC 5V 1.2A

Power Port, Downlink Port, Uplink Port

SWITCHING Power Adapter: MODEL: RD0501200-C55-KOG

INPUT: 100-240V~50/60Hz 250Ma

133MHz



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## 5. Test Summary

The product was tested in accordance with the following specifications. All testing has been performed according to below product classification:

#### **Test Results Summary**

Test Standard	Description	Product Class	Pass / Fail	
EN 55032:2015	Conducted Emissions	Class B	Pass	
EN 55032:2015	Radiated Emissions	Class B	Pass	
EN 61000-3-2: 2014	Harmonic Current Emissions	Class A	N/A*	
EN 61000-3-3: 2013	Limit of Voltage Change, Fluctuation & Flicker	Meets the requirements	Pass	

Test Standard	Description	Criterion	Pass / Fail
EN 55024: 2010			Γ
EN 61000-4-2: 2009	Electrostatic Discharge Immunity	В	Pass
EN 61000-4-3: 2006+A1:2008+A2: 2010	RF Electromagnetic Field Immunity	А	Pass
EN 61000-4-4: 2004+A1: 2010	Electrical Fast Transient / Burst Immunity	В	Pass
EN 61000-4-5: 2006	Voltage Surge Immunity	В	Pass
EN 61000-4-6: 2009	Conducted Disturbance Immunity	А	Pass
EN 61000-4-11: 2004	Voltage Dips And Interruption Immunity	B/C/C	Pass
EN 61000-4-8: 2010	Power-frequency Magnetic Fields Immunity	А	N/A

All measurement uncertainty is not taken into consideration for all presented test result.

\*Note: There is no need for Harmonics test to be performed on this product (rated power is less than 75W) in accordance with EN 61000-3-2.



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# 6. <u>MEASUREMENTS, EXAMINATION AND DERIVED RESULTS</u>

# 6.1 Conducted Emissions Test Result

Temperature	25°C
Relative Humidity	50%
Atmospheric Pressure	1019mbar
Test date :	7th August, 2016
Tested By :	Louise Tu

#### Conducted Emission Limit

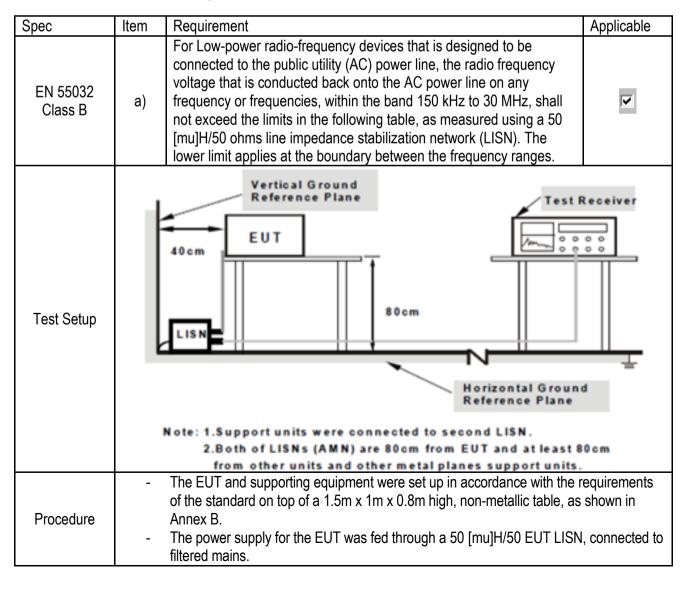
FREQUENCY (MHz)	Class A	A (dBµV)	Class B (dBµV)		
	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	79 66		66 - 56	56 - 46	
0.50 - 5.0	73 60		56	46	
5.0 - 30.0	73	60	60	50	

#### NOTE:

(1) The lower limit shall apply at the transition frequencies.

(2) The limit decreases in line with the logarithm of the frequency in the range of 0.15 to 0.50MHz.

(3) All emanations from a class A/B digital device or system, including any network of conductors and apparatus connected thereto, shall not exceed the level of field strengths specified above.





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	coaxial cable.	the EUT LISN was connected to the EMI test receiver via a low-loss ing equipment were powered separately from another main supply.
Result	Pass	Fail
Test Data	✓ Yes	□ <sub>N/A</sub>
Test Plot	Yes (See below)	□ <sub>N/A</sub>

#### Data sample

No. P/L	Erecuency	-						
	Frequency	Reading	Detector	Corrected	Result	Limit	Margin	Comment
	(MHz)	(dBuV)	QP	(dB}	(dBuV)	(dBuV)	(dB)	

P/L=Phase Line or Neutral

Frequency (MHz) = Emission frequency in MHz

Reading  $(dB\mu V)$  = Receiver Reading Value

Detector=Quasi Peak Detector or Average Detector

Corrected (dB) = cable loss+ Insertion loss of LISN+ Insertion loss of transient limiter (The transient limiter included 10dB attenuation)

Result (dBµV) = Reading Value + Corrected Value

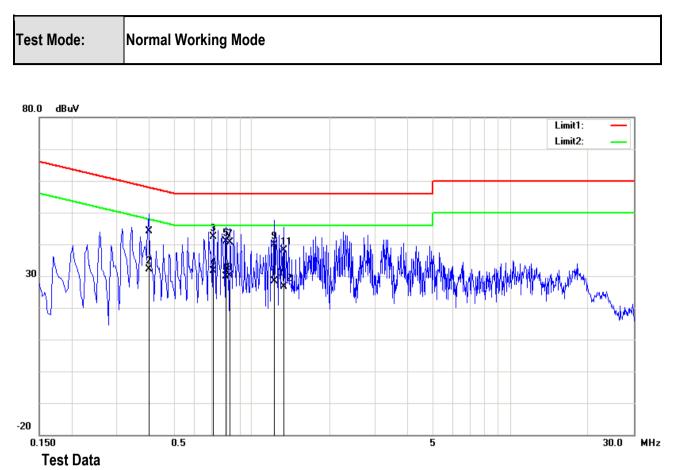
Limit (dB $\mu$ V) = Limit stated in standard

#### Calculation Formula:

Margin (dB) = Result (dB $\mu$ V) – limit (dB $\mu$ V)



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#### Phase Line Plot at 230Vac, 50Hz

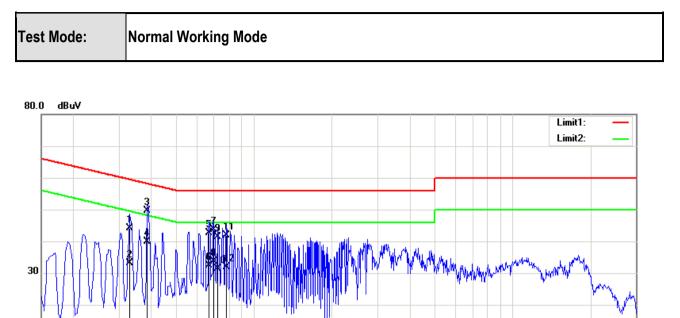
No.	P/L	Frequency	Reading	Detector	Corrected	Result	Limit	Margin	Comment
		(MHz)	(dBµV)		(dB}	(dBµV)	(dBµV)	(dB)	
1		0.3980	32.88	QP	11.23	44.11	57.90	-13.79	
2		0.3980	20.96	AVG	11.23	32.19	47.90	-15.71	
3		0.7100	31.58	QP	10.91	42.49	56.00	-13.51	
4		0.7100	20.74	AVG	10.91	31.65	46.00	-14.35	
5		0.7940	30.00	QP	10.84	40.84	56.00	-15.16	
6		0.7940	19.10	AVG	10.84	29.94	46.00	-16.06	
7		0.8220	29.93	QP	10.82	40.75	56.00	-15.25	
8		0.8220	19.22	AVG	10.82	30.04	46.00	-15.96	
9		1.2180	29.04	QP	10.72	39.76	56.00	-16.24	
10		1.2180	17.55	AVG	10.72	28.27	46.00	-17.73	
11		1.3300	27.36	QP	10.75	38.11	56.00	-17.89	
12		1.3300	15.93	AVG	10.75	26.68	46.00	-19.32	



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30.0

MHz





#### Phase Neutral Plot at 230Vac, 50Hz

No.	P/L	Frequency	Reading	Detector	Corrected	Result	Limit	Margin	Comment
		(MHz)	(dBµV)		(dB}	(dBµV)	(dBµV)	(dB)	
1		0.3300	32.88	QP	11.33	44.21	59.45	-15.24	
2		0.3300	21.88	AVG	11.33	33.21	49.45	-16.24	
3		0.3860	38.33	QP	11.24	49.57	58.15	-8.58	
4		0.3860	28.65	AVG	11.24	39.89	48.15	-8.26	
5		0.6700	31.73	QP	10.93	42.66	56.00	-13.34	
6		0.6700	21.40	AVG	10.93	32.33	46.00	-13.67	
7		0.6980	32.81	QP	10.91	43.72	56.00	-12.28	
8		0.6980	22.77	AVG	10.91	33.68	46.00	-12.32	
9		0.7220	30.46	QP	10.88	41.34	56.00	-14.66	
10		0.7220	20.44	AVG	10.88	31.32	46.00	-14.68	
11		0.7820	31.13	QP	10.84	41.97	56.00	-14.03	
12		0.7820	21.06	AVG	10.84	31.90	46.00	-14.10	



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#### 6.2 Radiated Emissions

Temperature	25°C
Relative Humidity	50%
Atmospheric Pressure	1019mbar
Test date :	7th August, 2016
Tested By :	Louise Tu

#### Limits below 1 GHz

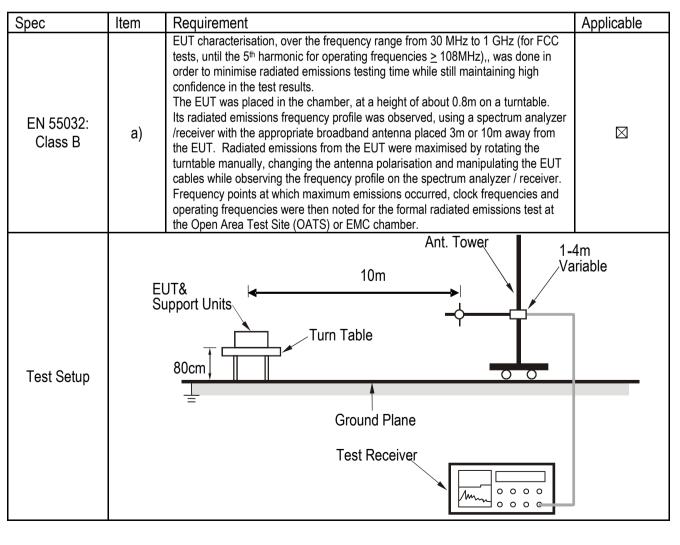
FREQUENCY (MHz)	dB(μV/m) (At 3m/10m) Class A	dB(μV/m) (At3m/10m) Class B
30 to 230	50/40	40/30
230 to 1000	57/47	47/37

Limits above 1 GHz

FREQUENCY	Class A dB(	μV/m) (At 3m)	Class B dB(µV/m) (At 3m)		
(GHz)	Average limit	Peak limit	Average limit	Peak limit	
1 to 3	56	76	50	70	
3 to 6	60	80	54	74	

NOTE: (1) The lower limit shall apply at the transition frequencies.

(2) Emission level dB ( $\mu$ V/m) = 20 log Emission level ( $\mu$ V/m)



3	
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Procedure 3 4	<ol> <li>The test was carried out at the selected frequency points obtained from the EUT characterisation. Maximization of the emissions, was carried out by rotating the EUT, changing the antenna polarization, and adjusting the antenna height in the following manner:         <ul> <li>a. Vertical or horizontal polarisation (whichever gave the higher emission level over a full rotation of the EUT) was chosen.</li> <li>b. The EUT was then rotated to the direction that gave the maximum emission.</li> <li>c. Finally, the antenna height was adjusted to the height that gave the maximum emission.</li> </ul> </li> <li>A Quasi-peak measurement was then made for that frequency point.</li> </ol>
	The radiated field measurement method above 1 GHz is based on measurement of the
Above 1GHz	The relation the evolution of the EUT as shown below           Valuated text volume (from site validation procedure)           Up to the value of value of the value of value of value of value of the value of the value of the value of the value of value of value of value of value of the value of value o



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	Frequency GHz	θ3 dB (min) °	ω <sub>m</sub>
	1	90	6.00
	2	60	3.46
	3	75	4.60
	4	60	3.46
	5	60	3.46
	6	50	2.80
	7	45	2.49
	8	40	2.18
	9	35	1.89
	10	30	1.61
	11	35	1.89
	12	40	2.18
	13	35	1.89
	14	35	1.89
	15	35	1.89
	16	35	1.89
	17	30	1.61
	18	20	1.06
	Note: The antenna's moving up an acceptable range of the testing antenn	d down is determined by $\omega$ value a can cover the whole range of EUT.	for above 1GHz, to ensure that the
Result	⊠ Pass □ Fai		
Test Data	⊠ Yes □ N/A	A	
Test Plot	⊠ Yes (See below) □ N/A	ł	



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#### Data sample

	- Calling										
No.	P/L	Frequency	Reading	Detector	Corrected	Result	Limit	Margin	Height	Degree	Comment
		(MHz)	(dBuV/m)		(dB/m)	(dBuV/m)	(dBuV/m)	(dB)	(cm)	( )	

P/L=Vertical or Horizontal of Receiver antenna

Frequency (MHz) = Emission frequency in MHz

Reading  $(dB\mu V/m)$  = Receiver Reading Value

Detector= Peak Detector or Quasi Peak Detector

Corrected (dB) = Antenna factor + cable loss- antenna gain

Result ( $dB\mu V/m$ ) = Reading Value + Corrected Value

Limit  $(dB\mu V/m)$  = Limit stated in standard

Height (cm) = Height of Receiver antenna

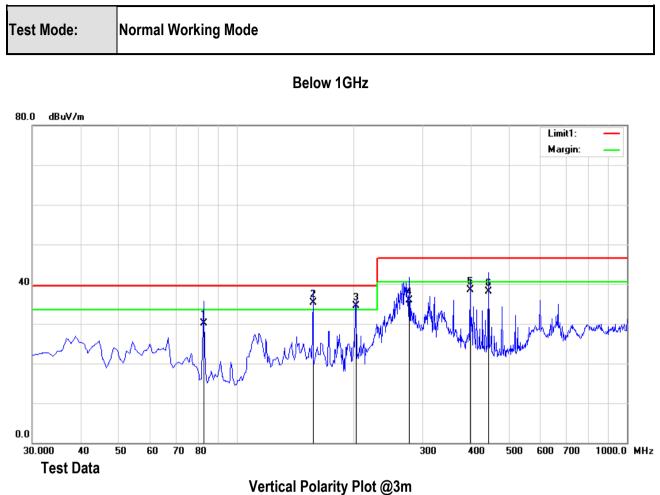
Degree = Turn table degree

#### Calculation Formula:

Margin (dB) = Result (dB $\mu$ V/m) – limit (dB $\mu$ V/m)



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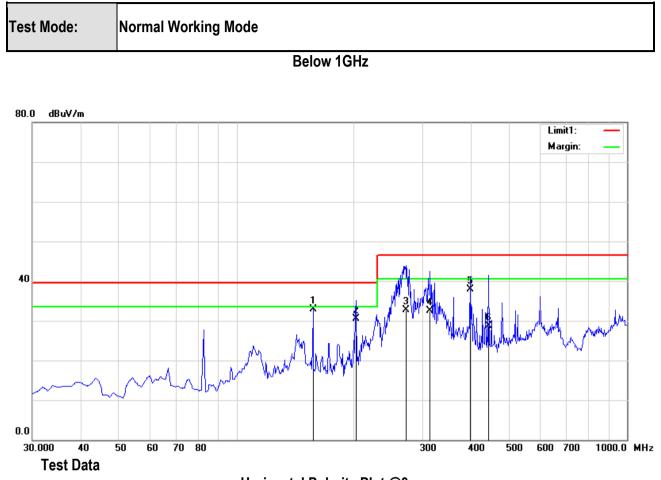


#### No. P/L Frequency Reading Detector Corrected Result Limit Margin Height Degree Comment (dB/m) (dBµV/m) (dBµV/m) (dB) (MHz) (dBµV/m) (cm) (°) QP 360 V 82.3800 66.97 -36.93 30.04 39.50 -9.46 140 1 2 157.0700 66.65 QP -31.32 35.33 39.50 99 V -4.17 119 3 V 202.6600 66.32 QP -31.90 34.42 39.50 -5.08 100 134 4 V 277.3500 QP -29.73 35.95 46.50 -10.55 200 15 65.68 V 397.6300 66.79 QP -28.36 38.43 46.50 -8.07 200 176 5 6 V QP 38.08 46.50 -8.42 99 79 442.2500 66.45 -28.37

Note: The data above 1GHz which below 20 dB to the limit was not recorded.



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#### Horizontal Polarity Plot @3m

No.	P/L	Frequency	Reading	Detector	Corrected	Result	Limit	Margin	Height	Degree	Comment
		(MHz)	(dBµV/m)		(dB/m)	(dBµV/m)	(dBµV/m)	(dB)	(cm)	(°)	
1	Н	157.0700	64.38	peak	-31.47	32.91	39.50	-6.59	100	74	
2	Н	202.6600	61.90	QP	-31.34	30.56	39.50	-8.94	200	343	
3	Н	271.5300	61.59	QP	-28.83	32.76	46.50	-13.74	200	323	
4	Н	314.2100	61.98	QP	-29.46	32.52	46.50	-13.98	99	124	
5	Н	397.6300	65.75	QP	-27.93	37.82	46.50	-8.68	99	285	
6	Н	442.2500	57.30	QP	-28.66	28.64	46.50	-17.86	99	347	

Note: The data above 1GHz which below 20 dB to the limit was not recorded.



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# 6.3 Voltage Fluctuation and Flicker Test Result

Temperature	25°C
Relative Humidity	50%
Atmospheric Pressure	1019mbar
Test date :	8th August, 2016
Tested By :	Louise Tu

Limits of voltage fluctuation and flicks measurement

Test item	Limit	Remark		
P <sub>st</sub>	1.0	P <sub>st</sub> means short-term flicker indicator.	P <sub>st</sub> means short-term flicker indicator.	
Pit	0.65	Plt means long-term flicker indicator.		
T <sub>dt</sub> (ms)	500	T <sub>dt</sub> means maximum time that dt exceeds 3.3 %.		
d <sub>max</sub> (%)	4%	d <sub>max</sub> means maximum relative voltage change.		
dc (%)	3.3%	dc means relative steady-state voltage change		

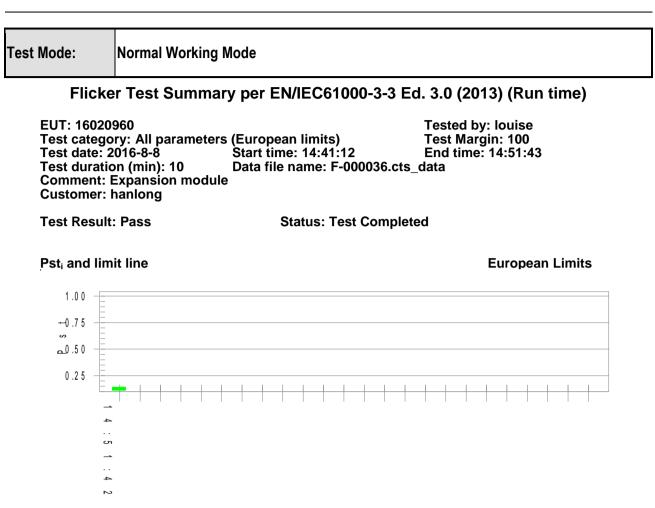
Spec	Item	Requirement	Applicable
EN 61000-3- 3:2013	a)	See Above Limits of voltage fluctuation and flicks measurement	
Test Setup	Fo Te	EUT 000 000 000 000 000 000 000 000 000 0	phs of the
Procedure	1. 2. 3.	The power supply to EUT was switched on and allowed to warm up to it operating condition. The voltage fluctuations and flickers measuring equipment was set to 23 Hz. The EUT was observed during, and checked after the test to determine	0 Vac with 50
Result	Pas	s Fail	
Test Data	✓ Yes	□ <sub>N/A</sub>	
Test Plot	✓ Yes	(See below)	



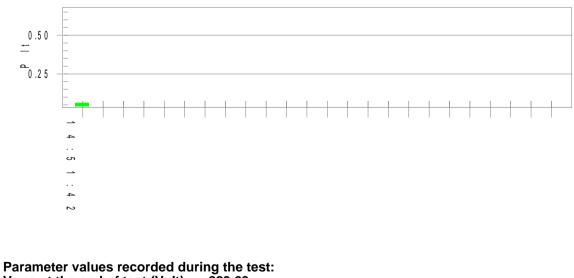
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#### Plt and limit line



Vrms at the end of test (Volt):	229.63			
Highest dt (%):	0.00	Test limit (%):	N/A	N/A
T-max (mS):	0	Test limit (mŚ):	500.0	Pass
Highest dc (%):	0.00	Test limit (%):	3.30	Pass
Highest dmax (%):	0.04	Test limit (%):	4.00	Pass
Highest Pst (10 min. period):	0.142	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.062	Test limit:	0.650	Pass
,				



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# 6.4 Harmonic Current Emission Test Result

Temperature	
Relative Humidity	
Atmospheric Pressure	
Test date :	
Tested By :	

Spec	Item	Requirement	Applicable
EN 61000-3- 2:2014	a)	Limits for Class A equipmentLimits for Class A equipmentMax. permissible 	
Test Setup	Fo	EUT OR BUT OR BUT OR BUT OF THE actual test configuration, please refer to the related item – Photogration.	aphs of the



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Procedure	<ol> <li>The power supply to EUT was switched on and allowed to warm up to its normal operating condition.</li> <li>The voltage fluctuations and flickers measuring equipment was set to 230 Vac with 50 Hz.</li> <li>The EUT was observed during, and checked after the test to determine the result.</li> </ol>	
Result	⊠N/A □Fail	
Test Data	⊠N/A □Fail	
Test Plot	⊠N/A □Fail	



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# 6.5 Electrostatic Discharge Immunity Test Result

Temperature	25°C
Relative Humidity	50%
Atmospheric Pressure	1019mbar
Test date :	8th August, 2016
Tested By :	Louise Tu

Discharge Type	Test Severity Level	Performance Criteria	Result
Air Discharges	$\pm 2$ kV, $\pm 4$ kV, $\pm 8$ kV	В	А
Indirect Discharge HCP	±2kV, ±4kV	В	А
Indirect Discharge VCP	±2kV, ±4kV	В	А

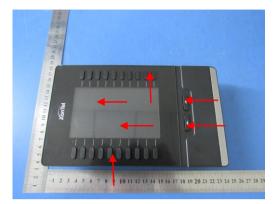
Spec	Item	Requirement	Applicable			
EN 61000-4- 2:2009	a)	<ol> <li>The test set-up was in accordance with the standard.</li> <li>The electrostatic discharge (ESD) gun was loaded with the correct charging / discharge network specified by the standard.</li> <li>A 0.8m high, non-metallic table, with a Horizontal Coupling Plane (HCP) placed on the tabletop, was used as a test bench. The EUT and supporting equipment were placed on the test bench, isolated from the HCP by a thin insulating sheet (0.5mm thick).</li> <li>The HCP was grounded to the ground plane via two 470 k "bleed" resistors at each end of the ground cable.</li> <li>A Vertical Coupling Plane (VCP) was also used during the test. The VCP was also grounded to the ground plane in a similar manner as the HCP.</li> </ol>				
Test Setup		$\frac{1}{10000000000000000000000000000000000$				
Procedure		Direct Air & Contact Discharges         Applications of direct air and contact discharges to the discharge points specifie customer were carried out in the following manner:         The EUT was switched on and allowed to warm up to its normal operating cond         The test discharge points are shown in the ESD Test Points Section of Annex B         For air discharges, the charged rounded electrode was positioned at a distance         test point and moved towards the EUT at a steady rate until a discharge was madelectrode touched the EUT, whichever occurs first.         For contact discharges, the pointed electrode was applied directly to the test point the conductive surface of the EUT. The discharges were then made with the	ition. away from the ade or until the int, in contact			

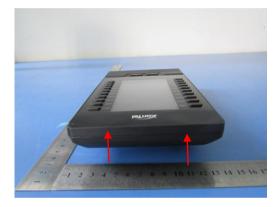
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	<ul> <li>one second interval betom The EUT was monitored the customer.</li> <li>Indirect Coupling Plane</li> <li>Indirect applications of EUT in the following matrix</li> <li>The EUT was switched The discharges to the Hard the required numbers a one second interval both The EUT was monitored the customer.</li> </ul>	tween discharge ed during the test <u>e Discharges</u> discharges using anner: I on and allowed HCP / VCP were of positive and n petween discharg ed during the test	in accordance with the Pass / Fail criteria declared by g the HCP & VCP were performed on the sides of the to warm up to its normal operating condition. made 0.1m away from one side of the EUT. egative discharges were applied at each test point; with
Test Mode	Normal Working		
Result	Pass Fail		



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Air Discharge: Contact Discharge:









For Air Discharge: (20 times per point and polarity and test level)

1 Plastic surface include EUT (20 points)

2 Slot in the EUT(20 points) 3 Screen in the EUT(20 points)

For Contact Discharge: (20 times per point and polarity and test level) 1 HCP 2 VCP



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# 6.6 RF Radiated Immunity Test Result

Temperature	25°C
Relative Humidity	50%
Atmospheric Pressure	1019mbar
Test date :	8th August, 2016
Tested By :	Louise Tu

	Item	Requirement	Applicable
EN 61000-4- 3:2006+A2:20 10	a)	All test measurements carried out are traceable to national standards. The uncertainty of the measurement at a confidence level of approximately 95% (in the case where distributions are normal), with a coverage factor of 2, in the range from 80MHz-2.7GHz, test level ranges from 3V/m to 10V/m, is $\pm$ 0.74V/m.	Z
Test Setup		Image: RF Amplifier       Image: RF Generator and control system       Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Image: Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Image: Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Image: Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Image: Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Image: Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Image: Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Image: Monitoring system         Image: RF Amplifier       Image: RF Generator and control system       Image: RF Generator and control system         Image: RF Amplifier       Image: RF Generator and control system       Image: RF Generator and control system         Image: RF Amplifier       Image: RF Generator and control system       Image: RF Generator and control system         Image: RF Amplifier       Image: RF Generator and control sys	aphs of the
	1		
Procedure	1. 2. 3. 4. 5.	<ul> <li>The EUT was switched on and allowed to warm up to its normal operating condition.</li> <li>The EUT was exercised and monitored in the manner specified by the customer.</li> <li>All test instruments were PC controlled, via their IEEE 488.2 bus interfaces, and the test following manner:</li> <li>a. The testing frequencies were swept over the required frequency range, with a equal to 1% of fundamental. The sweep rate was 1.0 x 10<sup>-3</sup> decades/s.</li> <li>b. For each frequency tested, the signal generator output level was adjusted auto unmodulated field strength registered by the field monitor reached the desire was held constant for the specified dwell time.</li> <li>The EUT was continuously monitored during the test in accordance with the Pass / Fail by the customer.</li> <li>The test was done in both horizontal and vertical antenna polarizations, and for all neces EUT.</li> </ul>	step frequency omatically until the d level. This level criteria declared
Procedure Test Mode	2. 3. 4. 5.	<ul> <li>The EUT was exercised and monitored in the manner specified by the customer.</li> <li>All test instruments were PC controlled, via their IEEE 488.2 bus interfaces, and the test following manner:</li> <li>a. The testing frequencies were swept over the required frequency range, with a equal to 1% of fundamental. The sweep rate was 1.0 x 10<sup>-3</sup> decades/s.</li> <li>b. For each frequency tested, the signal generator output level was adjusted auto unmodulated field strength registered by the field monitor reached the desire was held constant for the specified dwell time.</li> <li>The EUT was continuously monitored during the test in accordance with the Pass / Fail by the customer.</li> <li>The test was done in both horizontal and vertical antenna polarizations, and for all necessing the field monitor curve of the specified antenna polarizations.</li> </ul>	step frequency omatically until the d level. This level criteria declared



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# Test Result:

EUT AC Voltage Rating: 230Vac, 50Hz

Sides Tested	Frequency Range	Test Severity Level	Performance Criteria	Result
Front (H)	80 MHz – 1 GHz	3V/m, 80% AM (1kHz)	А	А
Front (V)	80 MHz – 1 GHz	3V/m, 80% AM (1kHz)	А	А
Back (H)	80 MHz – 1 GHz	3V/m, 80% AM (1kHz)	А	А
Back (V)	80 MHz – 1 GHz	3V/m, 80% AM (1kHz)	А	А
Right (H)	80 MHz – 1 GHz	3V/m, 80% AM (1kHz)	А	А
Right (V)	80 MHz – 1 GHz	3V/m, 80% AM (1kHz)	А	А
Left (H)	80 MHz – 1 GHz	3V/m, 80% AM (1kHz)	А	А
Left (V)	80 MHz – 1 GHz	3V/m, 80% AM (1kHz)	A	A



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# 6.7 Electrical Fast Transient/Burst Immunity Test Result

Temperature	25°C
Relative Humidity	50%
Atmospheric Pressure	1019mbar
Test date :	8th August, 2016
Tested By :	Louise Tu

Spec	ltem	Requirement	Applicable
EN 61000-4- 4:2004+A1:201 0	a)	All test measurements carried out are traceable to national standards. The uncertainty of the measurement at a confidence level of approximately 95% (in the case where distributions are normal), with a coverage factor of 2, test level ranges from $\pm 0.5$ kV to $\pm 1$ kV, is $\pm 1.2$ %.	
Test Setup			
Procedure	1. 2. 3. 4. 5.	<ul> <li>The EUT was switched on and allowed to warm up to its normal operating cond <u>D.C./A.C. Power Line Test</u></li> <li>a. The EFT/B test system has a built-in coupling/decoupling network which generated EFT bursts into the EUT power supply lines connected to it.</li> <li>b. The EFT bursts were coupled to the selected lines (one at a time) of the necessary test duration.</li> <li><u>I/O Signal &amp; Control Line Test</u></li> <li>The interference impulses were capacitively coupled to the EUT's signal cables necessary test duration.</li> <li>The EUT was monitored during the test in accordance with the Pass / Fail critt by the customer.</li> <li>The test was performed with EFT bursts in the positive and negative polarities on all necessary lines.</li> </ul>	ch couples the le EUT for the for the eria declared
Test Mode	Normal	Working Mode	
Result	Pas	s Fail	



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# Test Result:

EUT AC Voltage Rating: 230Vac, 50Hz

Test Point	Polarity	Test Level (kV)	Injected Method	Performance Criterion	Result
L	+/-	1	Direct	В	В
N	+/-	1	Direct	В	В
🖾 L–N	+/-	1	Direct	В	В



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# 6.8 Surge Immunity Test Result

Temperature	25°C
Relative Humidity	50%
Atmospheric Pressure	1019mbar
Test date :	8th August, 2016
Tested By :	Louise Tu

Spec	Item	Requirement	Applicable
EN 61000-4- 5:2006	a)	<ol> <li>The EUT was placed on a 0.8m high, non-conductive table.</li> <li>The test was performed using a voltage surge generator, mains, and signal line coupling/decoupling networks that were compliant with the standard.</li> <li>The voltage surge generator and coupling/decoupling networks were connected to the same protective earth.</li> <li>The test level was set with the surge generator's HV output opencircuited.</li> <li>For testing of the mains line, the mains coupling/decoupling network was inserted into the line. The voltage surge generator HV output cables were connected to the mains coupling/decoupling network was inserted into the line. The voltage surge generator HV output cables were connected to the mains coupling/decoupling network, which has the necessary resistor/capacitor configurations (as required by the standard) built-in. The settings on the mains coupling/decoupling network were selected to give the required resistor/capacitor configuration as follows:         <ul> <li>An 18µF capacitor in series with the output of the generator for differential (line-to-line) mode testing.</li> <li>A 10 Ohm resistor and 9µF capacitor in series with the output of the generator for common (line-to-ground) mode testing</li> </ul> </li> <li>For testing of the signal lines, the signal line coupling/decoupling network was inserted into the line. The voltage surge generator HV output cables were connected to the signal line coupling/decoupling network, which has the necessary resistor/capacitor/gas arrestor configurations (as required by the standard) built-in. The settings on this network were selected to give the required resistor/capacitor/gas arrestor configuration as reflected in the standard.</li> </ol>	

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Test Setup	Combination       ACDC Power Line (if any)         Wave Generator       Sgaal Line (if any)         L Sem       EUT         DecouplingNetwork       L Sem         Use of the second less configuration, please refer to the related item – Photographs of the fest Configuration.
Procedure	<ol> <li>The power supply to EUT was switched on and allowed to warm up to its normal operating condition.</li> <li>The surge generator phase shifter was set to 90° (for positive surges) or 270° (for negative surges).</li> <li>The correct open-circuit test level was set with the surge generator disconnected from the coupling network.</li> <li>The output of the generator was then reconnected back to the coupling network.</li> <li>Five discharges, generated by the voltage surge generator, were made on each relevant line, for each polarity, at each test level, with the relevant discharge interval.</li> <li>The EUT was observed during, and checked after the test to determine the result.</li> </ol>
Test Mode	Normal Working Mode
Result	Pass Fail

# Test Result:

# EUT AC Voltage Rating: 230Vac, 50Hz

The worst Phase angle is  $90^\circ$ 

Cable	Test Severity Level	Performance Criterion	Result
AC Power Input Port			
L1 + L2	1 kV	В	A



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# 6.9 Conducted Disturbance Immunity Test Result

Temperature	25°C
Relative Humidity	50%
Atmospheric Pressure	1019mbar
Test date :	8th August, 2016
Tested By :	Louise Tu

Spec	Item	Requirement	Applicable
EN 61000-4-6: 2009	a)	<ol> <li>The EUT and auxiliary equipment were placed on top of the GRP and isolated from it by a 0.1m thick insulating support as shown in <u>Annex B</u>.</li> <li>The test system includes a RF signal generator, a power amplifier, attenuators, a spectrum analyzer and various types of Coupling and Decoupling Networks (CDNs).</li> <li>The EUT's Cables under Test (CUT) were cut in order to insert the CDNs into the line. The cable lengths were kept as short as possible to maintain a distance of 0.1m to 0.3m between the EUT and the CDNs.</li> <li>The interconnecting cables between the EUT, CDNs and auxiliary equipment were kept at a height of 3cm to 5cm above the GRP.</li> <li>The CDNs were placed on the GRP, in direct electrical contact with it.</li> </ol>	Y
Test Setup		0.5m         0.5m      <	
Procedure	1. 2. 3. 4.	The EUT was switched on and allowed to warm up to its normal operating com The interfering signal was swept from 150 kHz to 80 MHz, with a step frequen of fundamental. The sweep rate was $\leq 1.5 \times 10^{-3}$ decades/s. The output power level from the power amplifier to the CDN was adjusted throug enerator so that the incident power reached the same level as that established calibration. Once the incident power to the CDN reached the calibrated level, kHz AF was switched on for the specified dwell time. The EUT was continuously monitored during the test in accordance with the P criteria declared by the customer.	cy equal to 1% ugh the signal ed during the 80% AM 1
Test Mode	Normal	Working Mode	
Result	Pase	s 🗖 Fail	



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# Test Result:

# EUT AC Voltage Rating: 230Vac, 50Hz

Frequency Band (MHz)	Field Strength (Vrms)	Cable	Injection Method	Performance Criterion	Result
0.15 ~ 80	3	Power Line	CDN-M2	А	A



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# 6.10 Voltage Dips And Interruption Immunity Test Result

Temperature	250°C
Relative Humidity	50%
Atmospheric Pressure	1019mbar
Test date :	8th August, 2016
Tested By :	Louise Tu

Spec	ltem	Requirement	Applicable
EN 61000-4-11: 2004	a)	<ol> <li>The proper severity level shall be selected before performing this testing.</li> <li>SIEMIC Work Instruction on this test must be referenced for the table of the Summary of Test Levels.</li> </ol>	V
Test Setup		Voltage Dips Generator AC Power Line EUT	
Procedure	1. 2.	The EUT was switched on and allowed to warm up to its normal operating The EUT shall continue to work as normal during the testing	ng condition.
Test Mode	Normal	Working Mode	
Result	Pase	s Fail	

# **Test Result:**

EUT AC Voltage Rating: 230Vac, 50Hz

	Duration (in Period)	Reduction (%)	Performance Criterion	Result
Voltage Dips	0.5 cycle	>95	В	А
Voltage Dips	25 cycle	30	С	В
Short Interruptions	250 cycle	>95	С	В



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# Annex A. TEST INSTRUMENT

Instrument	Model	Serial #	Cal Date	Cal Due	In use
Conducted Emissions	1 1				
R&S Receiver	ESPI3	101216	03/31/2016	03/31/2017	<b>v</b>
Transient Limiter	LIT-153	531021	10/30/2015	10/30/2016	<b>V</b>
TESEQ ISN	ISN T800	27093	03/31/2016	03/31/2017	N/A
R&S LISN(9k-30MHz)	ESH3-Z5	838979/005	03/31/2016	03/31/2017	~
SIEMIC EZ_EMC Conducted Emissions software	Ver.ICP-03A1	N/A	N/A	N/A	•
Radiated Emissions				1 1	
R&S Receiver	ESPI3	101216	03/31/2016	03/31/2017	
Hp Spectrum Analyzer	N9010A	MY47191130	03/31/2016	03/31/2017	$\checkmark$
HP Pre-amplifier	8447F	1937A01160	10/30/2015	10/30/2016	
MITEQ Pre-Amplifier(0.1 ~ 18GHz)	AMF-7D- 00101800-30-10P	1451710	10/27/2015	10/26/2016	V
Sunol Sciences, Inc. antenna (30MHz~6GHz)	JB6	A121411	10/31/2015	10/31/2016	
EMCO Horn Antenna (1~18GHz)	3115	N/A	10/09/2015	10/08/2016	~
SIEMIC EZ_EMC Radiated Emissions software	Ver.ICP-03A1	N/A	N/A	N/A	
Electrostatic Discharge Immunity					
ESD Generator	NSG 437	285	04/01/2016	04/01/2017	$\checkmark$
RF Electromagnetic Field Immunity					
Agilent Signal Generator	8665B	3744A01862	03/31/2016	03/31/2017	$\checkmark$
AR Power Amplifier	50W1000B	311309	Functional Verification		>
OPHIR Power Amplifier	5162R	1067	Functional V	erification	<b>v</b>
Sunol Sciences, Inc. antenna (30MHz~6GHz)	JB6	A121411	10/31/2015	10/31/2016	$\checkmark$
Fast Transients Common Mode					
EMC Immunity Test System	EMC PRO Plus	1111214	03/31/2016	03/31/2017	$\checkmark$
Surges Immunity					
EMC Immunity Test System	EMC PRO Plus	1111214	03/31/2016	03/31/2017	•
RF Common Mode Immunity					
Agilent Signal Generator	8665B	3744A01862	03/31/2016	03/31/2017	$\checkmark$
AR Power Amplifier	75A250	311662	Functional V	erification	>
Com-Power CDN	CDN M2	N/A	05/26/2016	05/25/2017	$\checkmark$
COM-POWER CDN T8	CDN T8	581540	05/24/2016	05/23/2017	N/A
Harmonic/ Fluctuations & Flicker/ Voltage	Dips Immunity				
California Instruments	3001 IX	58487	03/31/2016	03/31/2017	
California Instruments	PACS-1	72634	04/01/2016	04/01/2017	<b>v</b>



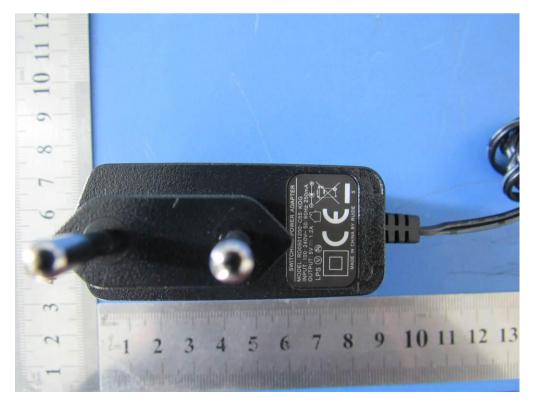
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# Annex B. EUT And Test Setup Photographs

#### Annex B.i. Photograph EUT External Photo



The Whole Package – Front View



Adapter - Front View



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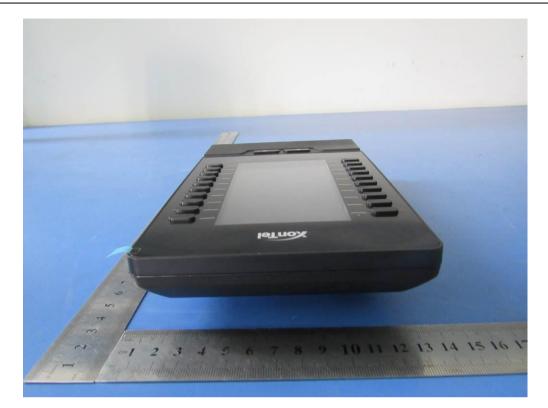
Front View of EUT



Rear View of EUT



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Top View of EUT



Bottom View of EUT



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Left View of EUT

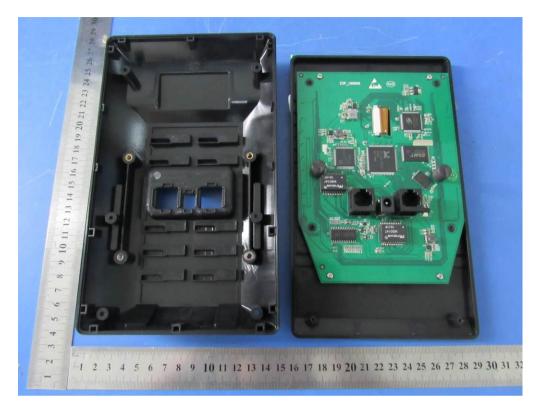


Right View of EUT

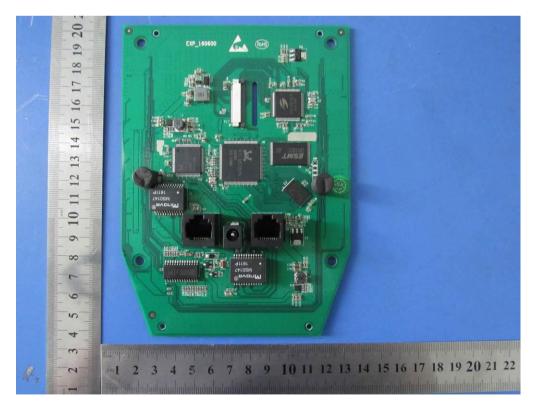


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#### Annex B.ii. Photograph EUT Internal Photo



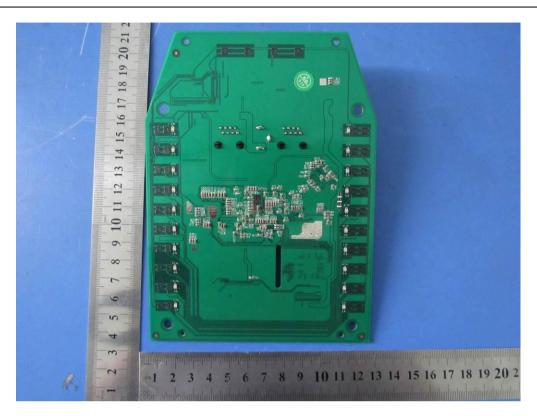
EUT – Uncover Front View



PCB- Front View



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PCB- Rear View



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#### Annex B.iii. Photograph Test Setup Photo



Conducted Emissions Test Setup - Front View

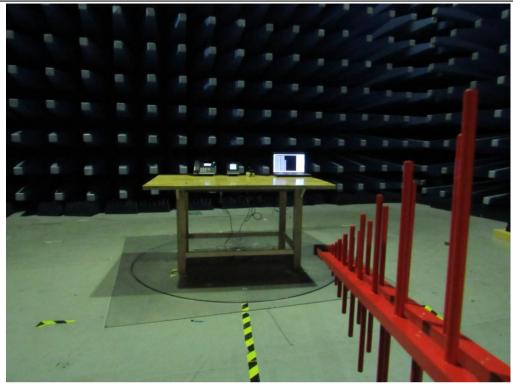


Conducted Emissions Test Setup - Side View

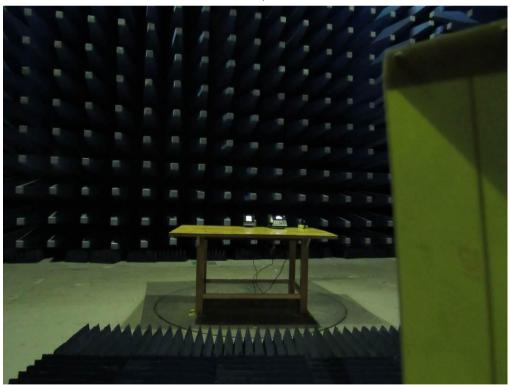


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Radiated Emissions Test Setup Below 1GHz - Front View



Radiated Emissions Test Setup Above 1GHz - Front View

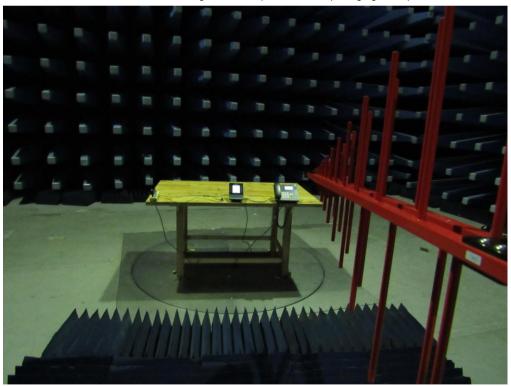


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Electrostatic Discharge Test Setup - Front View(Charging Mode)



RF Electromagnetic Field Immunity Test Setup - Rear View



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Surge & Fast Transients Common Mode Immunity Test Setup - Front View



Conducted Disturbance Immunity Test Setup - Front View



Voltage Fluctuations And Flicker Test Setup Front View

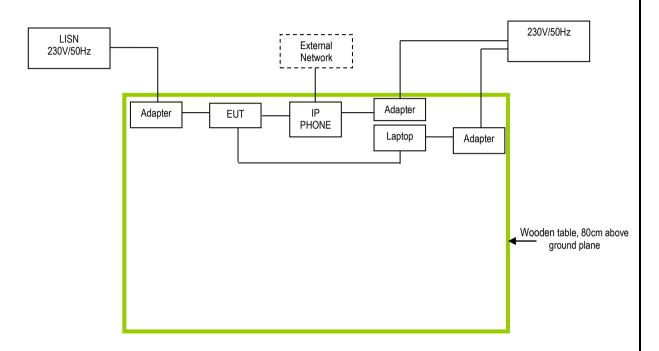


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## Annex C. TEST SETUP AND SUPPORTING EQUIPMENT

#### Annex C.i. TEST SET UP BLOCK

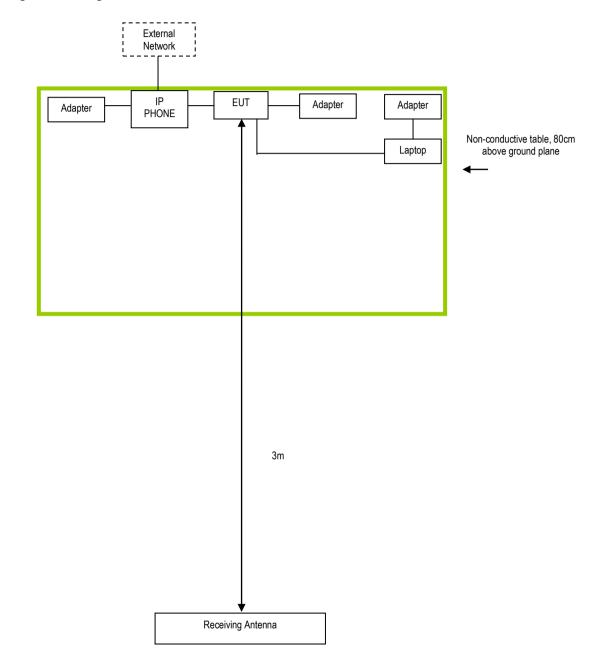
**Block Configuration Diagram for Conducted Emissions** 





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#### Block Configuration Diagram for Radiated Emissions





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#### Annex C. ii. SUPPORTING EQUIPMENT DESCRIPTION

The following is a description of supporting equipment and details of cables used with the EUT.

Manufacturer	Equipment Description	Model
Dell	Laptop	3421
N/A	IP PHONE	S500



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# Annex D. User Manual / Block Diagram / Schematics / Partlist

Please see attachment



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### Annex E. DECLARATION OF SIMILARITY

#### Nanjing Hanlong Technology Co., Ltd.

#### Statement

We Nanjing Hanlong Technology Co., Ltd. agree SAHAB TECHNOLOGY to use below information on file to apply a multiple-listing certification.

Original Information: Model name: UC46 Product Description: EXPANSION MODULE Brand: Htek Applicant name: Nanjing Hanlong Technology Co., Ltd. Applicant address: 5th Floor, 1st Building, Huashen Tech Park, 10 Huashen Temple, Yuhuatai Dis, Nanjing China Manufacturer name: Nanjing Hanlong Technology Co., Ltd. Manufacturer address: 5th Floor, 1st Building, Huashen Tech Park, 10 HuashenTemple, Yuhuatai Dis, Nanjing China

New Information: Model name: XT-23EXP Product Description: EXPANSION MODULE Brand: XonTel Applicant name: SAHAB TECHNOLOGY Applicant address: Office 21,Qibla Tower,Fahad Al Salem St.,Qibla, State of KUWAIT Manufacturer name: SAHAB TECHNOLOGY Manufacturer address: Office 21,Qibla Tower,Fahad Al Salem St.,Qibla, State of KUWAIT

We hereby state that these models are identical in interior structure, electrical circuits and components, and just model names are different for the marketing requirement.

Your assistance on this matter is highly appreciated.

Sincerely, Name: Julex Title: Marketing Director

Sundax Signature: